## Open Peer Review on Qeios

## Secondary Ion Mass Spectrometry

National Cancer Institute

## Source

*National Cancer Institute. <u>Secondary Ion Mass Spectrometry</u>. NCI Thesaurus. Code C154790.* 

An analytical technique in which a mass spectrometer is used to detect sputtered ionized atoms (secondary ions) that are ejected from a solid surface after application of a beam of high energy primary ions.